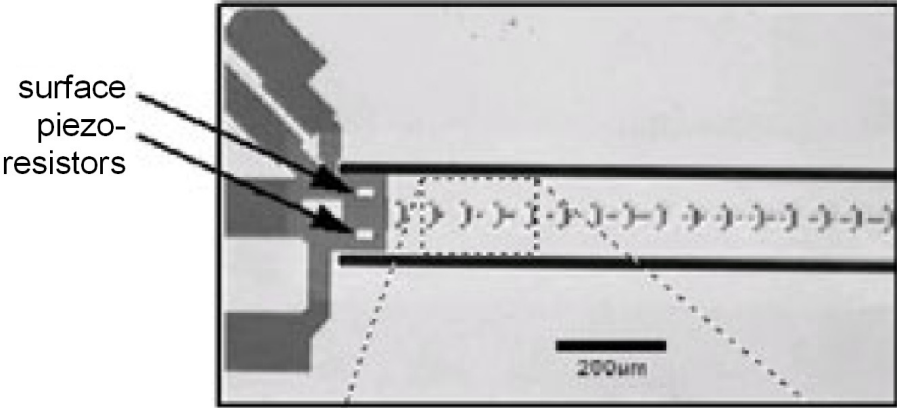
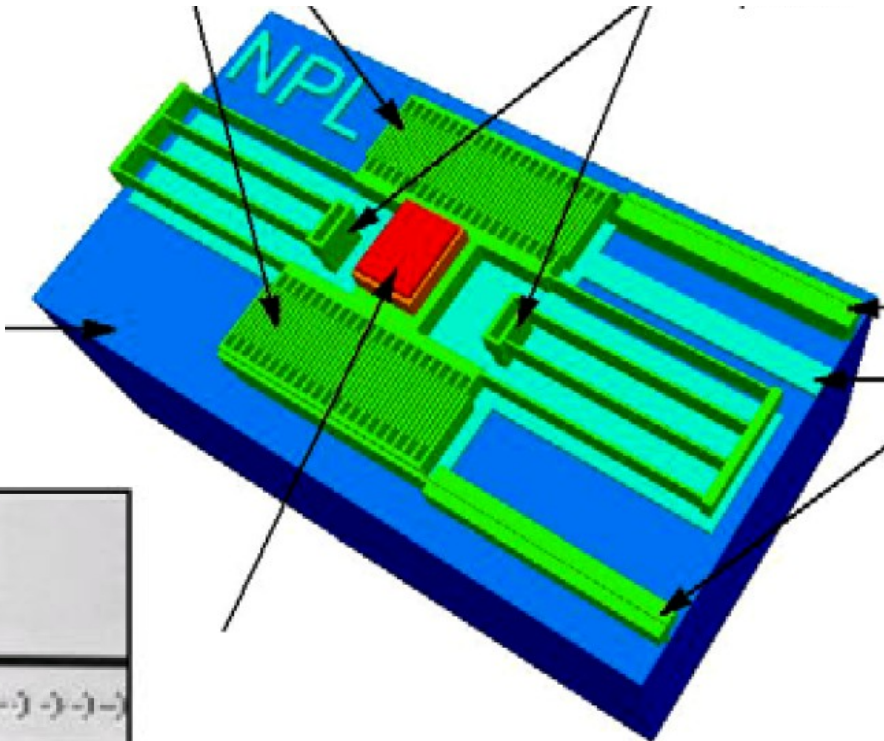
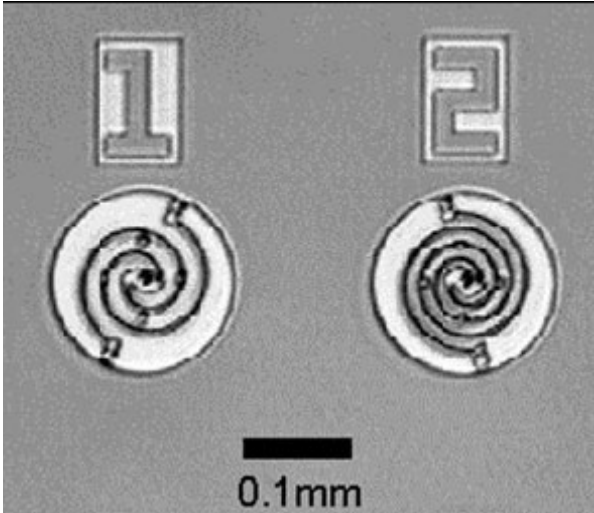


Low force transfer artefacts

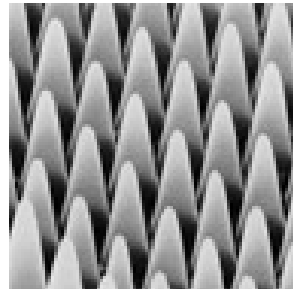
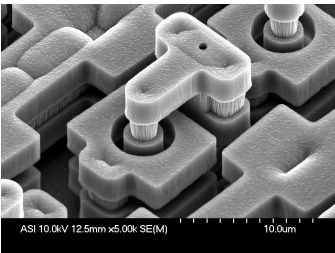


NMS Engineering Measurement Programme Oct 2008 – Sep 2011

- Measurement and characterisation of areal surfaces
- Development of a Centre for Freeform Measurement
- Traceable micro-coordinate metrology of complex miniature parts
- An infrastructure for low force measurement
- Metrology for atomic force microscopes
- X-ray interferometry to support optical metrology
- XCT?

Conclusions

- In order to control manufacturing, measurement is essential
- This applies at ALL scales
- Metrology allows the interchangeability of parts but only if the measurements are traceable
- More research is required to make existing instruments traceable and to develop new instrumentation
- Good practice guidance essential



Fundamental Principles of Engineering Nanometrology

(Elsevier, Sept 09)

by Richard Leach

A blatant plug!

Thank you – any questions?

